



REPORT No.: SZ25060440S01

## Annex G DASY Calibration Certificate



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Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: **SCS 0108**

Client

**Morlab**  
Shenzhen City

Certificate No.

**EX-7608\_Mar25**

## CALIBRATION CERTIFICATE

Object EX3DV4 - SN:7608

Calibration procedure(s) QA CAL-01.v10, QA CAL-12.v10, QA CAL-14.v7, QA CAL-23.v6,  
QA CAL-25.v8  
Calibration procedure for dosimetric E-field probes

Calibration date March 20, 2025

This calibration certificate documents the traceability to national standards, which realize the physical units of measurements (SI).  
The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature  $(22 \pm 3)^\circ\text{C}$  and humidity  $< 70\%$ .

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID	Calibration Date (Certificate No.)	Sched. Cal.
Power Sensor R&S NRP-33T	SN: 100967	28-Mar-24 (No. 217-04038)	Mar-25
Short [S6019i] + Attenuator [S6020i]	SN: L1119	26-Mar-24 (No. 217-04048)	Mar-25
OCP DAK-12	SN: 1016	24-Sept-24 (No. OCP-DAK12-1016_Sep24)	Sep-25
OCP DAK-3.5	SN: 1249	23-Sept-24 (No. OCP-DAK3.5-1249_Sep24)	Sep-25
Reference Probe EX3DV4	SN: 7349	10-Jan-25 (No. EX3-7349_Jan25)	Jan-26
DAE4	SN: 1301	07-Nov-24 (No. DAE4-1301_Nov24)	Nov-25

Secondary Standards	ID	Check Date (in house)	Sched. Check
ACAP 2020 Calibration Box	SN: L1404	30-Sept-24 (No. Report_ACAP2020E-Cave_20240930s)	Sep-25

	Name	Function	Signature
Calibrated by	Aidonia Georgiadou	Laboratory Technician	
Approved by	Sven Kühn	Technical Manager	
			Issued: March 20, 2025
This calibration certificate shall not be reproduced except in full without written approval of the laboratory.			



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## Glossary

TSL	tissue simulating liquid
NORM <sub>x,y,z</sub>	sensitivity in free space
ConvF	sensitivity in TSL / NORM <sub>x,y,z</sub>
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A, B, C, D	modulation dependent linearization parameters
Polarization $\varphi$	$\varphi$ rotation around probe axis
Polarization $\vartheta$	$\vartheta$ rotation around an axis that is in the plane normal to probe axis (at measurement center), i.e., $\vartheta = 0$ is normal to probe axis
Connector Angle	information used in DASY system to align probe sensor X to the robot coordinate system

## Calibration is Performed According to the Following Standards:

- IEC/IEEE 62209-1528, "Measurement Procedure For The Assessment Of Specific Absorption Rate Of Human Exposure To Radio Frequency Fields From Hand-Held And Body-Worn Wireless Communication Devices – Part 1528: Human Models, Instrumentation And Procedures (Frequency Range of 4 MHz to 10 GHz)", October 2020.
- KDB 865664, "SAR Measurement Requirements for 100 MHz to 6 GHz"

## Methods Applied and Interpretation of Parameters:

- NORM<sub>x,y,z</sub>**: Assessed for E-field polarization  $\vartheta = 0$  ( $f \leq 900$  MHz in TEM-cell;  $f > 1800$  MHz: R22 waveguide). NORM<sub>x,y,z</sub> are only intermediate values, i.e., the uncertainties of NORM<sub>x,y,z</sub> does not affect the E<sup>2</sup>-field uncertainty inside TSL (see below ConvF).
- NORM(f)<sub>x,y,z</sub>** = NORM<sub>x,y,z</sub> \* frequency\_response (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of ConvF.
- DCP<sub>x,y,z</sub>**: DCP are numerical linearization parameters assessed based on the data of power sweep with CW signal. DCP does not depend on frequency nor media.
- PAR**: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics
- A<sub>x,y,z</sub>; B<sub>x,y,z</sub>; C<sub>x,y,z</sub>; D<sub>x,y,z</sub>; VR<sub>x,y,z</sub>**: A, B, C, D are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- ConvF and Boundary Effect Parameters**: Assessed in flat phantom using E-field (or Temperature Transfer Standard for  $f \leq 800$  MHz) and inside waveguide using analytical field distributions based on power measurements for  $f > 800$  MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty values are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORM<sub>x,y,z</sub> \* ConvF whereby the uncertainty corresponds to that given for ConvF. A frequency dependent ConvF is used in DASY version 4.4 and higher which allows extending the validity from  $\pm 50$  MHz to  $\pm 100$  MHz.
- Spherical isotropy (3D deviation from isotropy)**: in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset**: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle**: The angle is assessed using the information gained by determining the NORM<sub>x</sub> (no uncertainty required).



## Parameters of Probe: EX3DV4 - SN:7608

### Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc ( $k = 2$ )
Norm ( $\mu\text{V}/(\text{V/m})^2$ ) <sup>A</sup>	0.68	0.65	0.70	$\pm 10.1\%$
DCP (mV) <sup>B</sup>	109.0	106.8	109.3	$\pm 4.7\%$

### Calibration Results for Modulation Response

UID	Communication System Name		A dB	B $\text{dB}\sqrt{\mu\text{V}}$	C	D dB	VR mV	Max dev.	Max Unc <sup>E</sup> $k = 2$
0	CW	X	0.00	0.00	1.00	0.00	126.0	$\pm 1.8\%$	$\pm 4.7\%$
		Y	0.00	0.00	1.00		128.3		
		Z	0.00	0.00	1.00		127.2		
10352	Pulse Waveform (200Hz, 10%)	X	1.65	61.13	6.65	10.00	60.0	$\pm 2.9\%$	$\pm 9.6\%$
		Y	1.68	61.26	6.73		60.0		
		Z	1.65	61.13	6.64		60.0		
10353	Pulse Waveform (200Hz, 20%)	X	0.85	60.00	5.04	6.99	80.0	$\pm 2.5\%$	$\pm 9.6\%$
		Y	10.00	72.00	9.00		80.0		
		Z	0.85	60.00	5.03		80.0		
10354	Pulse Waveform (200Hz, 40%)	X	0.46	60.00	3.93	3.98	95.0	$\pm 2.8\%$	$\pm 9.6\%$
		Y	0.00	118.66	0.96		95.0		
		Z	0.47	60.00	3.93		95.0		
10355	Pulse Waveform (200Hz, 60%)	X	13.80	155.28	12.55	2.22	120.0	$\pm 1.6\%$	$\pm 9.6\%$
		Y	0.69	158.31	1.39		120.0		
		Z	13.98	155.20	13.38		120.0		
10387	QPSK Waveform, 1 MHz	X	0.56	62.93	11.67	1.00	150.0	$\pm 4.0\%$	$\pm 9.6\%$
		Y	0.70	63.22	11.36		150.0		
		Z	0.59	63.11	11.76		150.0		
10388	QPSK Waveform, 10 MHz	X	1.32	65.13	13.42	0.00	150.0	$\pm 1.5\%$	$\pm 9.6\%$
		Y	1.40	64.45	13.10		150.0		
		Z	1.34	65.18	13.50		150.0		
10396	64-QAM Waveform, 100 kHz	X	1.78	65.09	15.96	3.01	150.0	$\pm 0.9\%$	$\pm 9.6\%$
		Y	1.61	63.22	15.13		150.0		
		Z	1.77	65.02	15.92		150.0		
10399	64-QAM Waveform, 40 MHz	X	2.81	66.07	14.82	0.00	150.0	$\pm 2.0\%$	$\pm 9.6\%$
		Y	2.73	64.80	14.15		150.0		
		Z	2.83	66.05	14.83		150.0		
10414	WLAN CCDF, 64-QAM, 40 MHz	X	3.81	65.77	15.03	0.00	150.0	$\pm 3.7\%$	$\pm 9.6\%$
		Y	4.01	65.54	14.97		150.0		
		Z	3.84	65.72	15.04		150.0		

Note: For details on UID parameters see Appendix

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor  $k=2$ , which for a normal distribution corresponds to a coverage probability of approximately 95%.

<sup>A</sup> The uncertainties of Norm X,Y,Z do not affect the  $E^2$ -field uncertainty inside TSL (see Pages 5 and 6).

<sup>B</sup> Linearization parameter uncertainty for maximum specified field strength.

<sup>E</sup> Uncertainty is determined using the max. deviation from linear response applying rectangular distribution and is expressed for the square of the field value.

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### Sensor Model Parameters

	C1 fF	C2 fF	$\alpha$ $V^{-1}$	T1 $ms V^{-2}$	T2 $ms V^{-1}$	T3 ms	T4 $V^{-2}$	T5 $V^{-1}$	T6
x	10.3	72.03	31.68	4.33	0.00	4.90	0.60	0.00	1.00
y	13.1	94.33	33.00	2.61	0.00	4.91	0.40	0.00	1.01
z	10.7	75.41	31.88	4.41	0.00	4.90	0.61	0.00	1.00

### Other Probe Parameters

Sensor Arrangement	Triangular
Connector Angle	-25.4°
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disabled
Probe Overall Length	337 mm
Probe Body Diameter	10 mm
Tip Length	9 mm
Tip Diameter	2.5 mm
Probe Tip to Sensor X Calibration Point	1 mm
Probe Tip to Sensor Y Calibration Point	1 mm
Probe Tip to Sensor Z Calibration Point	1 mm
Recommended Measurement Distance from Surface	1.4 mm

**Note:** Measurement distance from surface can be increased to 3–4 mm for an *Area Scan* job.